



51FW

**PATENT APPLICATION**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re the Application of:

Confirmation No.: 5311

MARUYAMA

Art Unit: 2857

Application No.: 10/791,725

Examiner: M. Charioui

Filed: March 4, 2004

Docket No.: 108131-00004

For: INTEGRATED CIRCUIT TESTING METHOD, PROGRAM, STORING MEDIUM,  
AND APPARATUS

**AMENDMENT UNDER 37 C.F.R. § 1.121**

**Introductory Comments**

Director of the U.S. PTO  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

September 13, 2005

Sir:

In response to the Office Action dated June 21, 2005, please amend the above-  
titled application as follows: